

EMC TEST REPORT

Equipment USB type C plug to HDMI plug cable

Trade mark /

Model No. FTSA01, FTSA02, FTSA03

Report No. FullStrike.LTD

Applicant Room 2801, International Technology Building, ShenNan Road, Futian

district, SZ, 518033 PRC

FullStrike.LTD

Manufacturer No. 123 Building A, Investment & Venture Center, Jinhui West Road,

Yinzhou Dist., Ningbo City, Zhejiang Provice, China

Shenzhen CTB Testing Technology Co., Ltd.

Prepared by Floor 1&2, Building A, No. 26 of Xinhe Road, Xinqiao Street, Baoan

District, Shenzhen China

Tel: 4008-707-283

Fax: 086-0755-23208027

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Test Standard(s) EN 55032:2015, EN 55035:2017/A11:2020

In the configuration tested, the EUT complied with the standards specified above.

Producer: Amy Yang , Date : Apr. 26, 2021

Amy Yang / Engineer

Signatory: Date: Apr. 26, 2021

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1. TEST SUMMARY

	Emission			
Requirement - Test	Test Method	Limit	Result	
Conducted Emission	0,0,0,0,0	Class B	N/A	
Radiated emissions at frequencies up to 1 GHz	EN 55032:2015	Class B	PASS	
Radiated emissions at frequencies above 1 GHz		Class B	N/A	
Harmonic current emissions EN IEC 61000-3-2:2019		Class A	N/A	
Voltage changes, voltage fluctuations and flicker EN 61000-3-3:2013/A1:2019		Clause 5	N/A	
Imn	nunity (EN 55035:2017/A11:2020)			
Requirement - Test	Test Method	Performance criteria	Result	
Electrostatic discharges (ESD)	EN 61000-4-2:2009	9	PASS	
Electromagnetic field	EN 61000-4- 3:2006+A1:2008+A2:2010	A	PASS	
Electrical fast transients/burst (EFT/B)	EN 61000-4-4:2004+A1:2010	В	N/A	
Surges	EN 61000-4-5:2006	В	N/A	
Conducted RF	EN 61000-4-6:2009	A	N/A	
Power frequency magnetic field	EN 61000-4-8:2010	A A	N/A	
Voltage dips and Short interruptions	EN 61000-4-11:2009+A1:2010	B & C	N/A	

Remark: N/A is abbreviation for Not Applicable.

The test was carried out in all the test modes, only the worst data are list in report.



2. GENERAL INFORMATION

2.1. Description of EUT

Equipment	USB type C plug to HDMI plug cable
Trademark	
Model Name	C 520-2 L
Serial No.	FTSA01, FTSA02, FTSA03
Model Difference	All model's the function, software and electric circuit are the same, only with a product color and model named different. Test sample model: C 520-2 L
Rated Power Supply	DC 5V
Rated Power	10 0 0 0 0 0 0 0 0 0 0
Normal Testing Voltage	DC 5V from PC
Configuration	
Accessory Device	Pc+Notebook
Cable Supplied	USB

Note:

1. Other Accessory Device List and Details

Description	Manufacturer	Model	Note
		0 0	

External I/O Cable

Á	Cable Description	Shielded Type	Ferrite Core	Length(m)	Note
		☐Shielded ☐Non-shielded	□Yes □No	\$ 0	\$ \$
	Y 54 54 6		CA CA CA	5,00	CAY CAY

2. The above EUT information is declared by manufacturer and for more detailed features description, please refer to the manufacturer's specifications or the User's Manual.



2.2. Operating condition of EUT

To investigate the maximum EMI emission characteristics generates from EUT, the test system was pre-scanning tested base on the consideration of following EUT operation mode or test configuration mode which possible have effect on EMI emission level. Each of these EUT operation mode(s) or test configuration mode(s) mentioned above was evaluated respectively

Pretest Mode	Description
Mode 1	Working

For Conducted Test					
Final Test Mode	Description				
Mode 1	Working				
Mode 2	charge				

For Radiated Test					
Final Test Mode	Description				
Mode 1	Working				
Mode 2	charge				

2.3. Test conditions

Temperature: 15-35℃ Relative Humidity: 30-60 %

Atmospheric pressure: 800hPa-1060hPa

2.4. Block diagram of EUT configuration





3. FACILITIES

3.1. Test Facility

CTB-LAB

Floor 1&2, Building A, No. 26 of Xinhe Road, Xinqiao Street, Baoan District, Shenzhen China

3.2. Test Instruments

Radiated Emission Measurement (Test software: EZ-EMC Ver. FA-03A2 RE)

Item	Equipment	Manufacturer	Model No.	Serial No.	Calibrated until
1	Double Ridged Broadband Horn Antenna	Schwarzbeck	BBHA 9120D	1911	2021.11.02
2	TRILOG Broadband Antenna	Schwarzbeck	VULB 9168	869	2021.11.02
3	Amplifier	Agilent	8449B	3008A01838	2021.11.01
4	Amplifier	HP	8447E	2945A02747	2021.11.01
5	EMI TEST RECEIVER	ROHDE&SCHWARZ	ESPI7	100362	2021.11.01
6	Coaxial cable	ETS	RFC-SNS- 100-NMS-80 NI	\$ 1\$ C	2021.11.01
7	Coaxial cable	ETS	RFC-SNS- 100-NMS-20 NI		2021.11.01
8	Coaxial cable	ETS	RFC-SNS- 100-SMS-20 NI		2021.11.01
9	Coaxial cable	ETS	RFC-NNS- 100-NMS- 300 NI		2021.11.01

Electrostatic Discharge Test

Item	Equipment	Manufacturer	Model No.	Serial No.	Calibrated until
10	ESD Simulator	TESTQ	NSG437	329	2021.10.30

RF electromagnetic field Test

Item	Equipment	Manufacturer	Type No.	Serial No.	Calibrated until
1	Signal Generator	Agilent	N5182A	MY47420195	2021.10.30
2	Log-Bicon Antenna	Schwarzbeck	VULB9161	9128ES-128	2021.10.30
3	Power Amplifier	AR	150W1000M1	342526	2021.10.30
4	Microwave Horn Antenna	AR	AT4002A	322279	2021.10.30
5	Power Amplifier	AR	25S1G4A	321116	2021.10.30



4. Measurement uncertainty

The following table is for the measurement uncertainty, which is calculated as per the document CISPR 16-4.

Test	Parameters	Expanded Uncertainty (U _{Lab})	Expanded Uncertainty (Ucispr)	
Conducted Emission	Level Accuracy: 150kHz to 30MHz	±1.22 dB	±3.6 dB	
Radiated Emission	Level Accuracy: 30MHz to 1000 MHz	±3.67 dB	±5.2 dB	
Radiated Emission	Level Accuracy: Above 1000MHz	±4.79 dB	N/A	

This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of k=2.



5. Emission

5.1. Conducted Emission

5.1.1. Limit

Requirements for conducted emissions from the AC mains power ports of Class A equipment

Frequency range MHz	Coupling device	Detector type / bandwidth	Class A limits dB(μV)
0,15 to 0,5	4 4 4	Ouesi Beek / Okl la	79
0,5 to 30	AMN	Quasi Peak / 9 kHz	73
0,15 to 0,5	AIVIIN	Average / O kl la	66
0,5 to 30	7 62 62	Average / 9 kHz	60

Requirements for conducted emissions from the AC mains power ports of Class B equipment

Frequency range MHz	Coupling device	Detector type / bandwidth	Class B limits dB(µV)
0,15 to 0,5	V V V V	KY KY KY	66 to 56
0,5 to 5	0' 0' 0'	Quasi Peak / 9 kHz	56
5 to 30	S ANANO 4	h 40 40 40	60
0,15 to 0,5	AMN	4. 4.	56 to 46
0,5 to 5	0 0 0	Average / 9 kHz	46
5 to 30	0 0 0 0	0 0 0	50

Requirements for asymmetric mode conducted emissions from Class A equipment

Frequency range MHz	Coupling device	Detector type / bandwidth	Class A limits dB(µV)
0,15 to 0,5 0,5 to 30	4 4 4 C	Quasi Peak / 9 kHz	97 to 87 87
0,5 to 30	AAN	Average / 0 kl l=	84 to 74
0,5 to 30	CA CA C	Average / 9 kHz	74

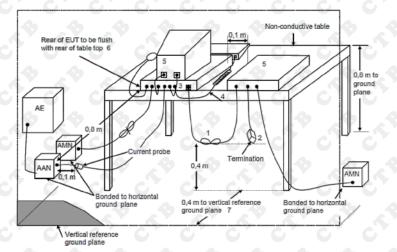
Requirements for asymmetric mode conducted emissions from Class B equipment

Frequency range MHz	Coupling device	Detector type / bandwidth	Class B limits dB(µV)
0,15 to 0,5	Y Y Y	Quasi Peak / 9 kHz	84 to 74
0,5 to 30	AAN	Quasi Feak / 9 Ki iz	74
0,15 to 0,5	AAN	Average / 9 kHz	74 to 64
0,5 to 30	V. V. V	Average / 9 kHz	64

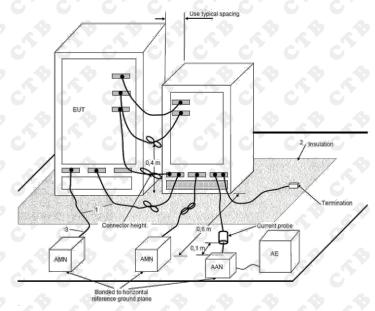


5.1.2. Test setup

For table-top equipment



For floor standing equipment



5.1.3. Test procedure

Measurement was performed in shielded room, and instruments used were followed CISPR 16-2-1 clause7.

Detailed test procedure was following clause 7 of CISPR 16-2-1.

Frequency range 150kHz – 30MHz was checked and EMI receiver measurement bandwidth was set to 9 kHz.

5.1.4. Test results

N/A



5.2. Radiated emissions

5.2.1. Limit

Requirements for radiated emissions at frequencies up to 1 GHz for class A equipment

Frequency		Class B limits		
range MHz	Facility	Distance m	Detector type / bandwidth	dB(µV/m)
30 to 230	SAC	0	Quasi Peak /	50
230 to 1 000	SAC	3 9	120 kHz	57

Requirements for radiated emissions at frequencies above 1 GHz for class A equipment

Frequency		Class B limits		
range MHz	Facility	Distance m	Detector type / bandwidth	dB(µV/m)
1 000 to 3 000	0,0	0	Average /	56
3 000 to 6 000	FCOATC	4 3 4 b	1MHz	60
1 000 to 3 000	FSOATS		Average /	76
3 000 to 6 000	A A	3	1MHz	80

Requirements for radiated emissions at frequencies up to 1 GHz for class B equipment

•	Frequency	The Car	Class D limits			
>	range MHz	Facility	Distance m	Detector type / bandwidth	Class B limits dB(µV/m)	
	30 to 230 230 to 1 000	SAC	3	Quasi Peak / 120 kHz	40 47	

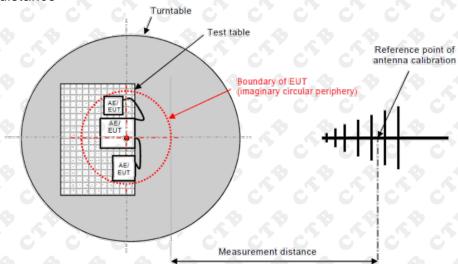
Requirements for radiated emissions at frequencies above 1 GHz for class B equipment

Frequency	A VA	Class D limits		
range MHz	Facility	Distance m	Detector type / bandwidth	Class B limits dB(µV/m)
1 000 to 3 000			Average /	50
3 000 to 6 000	FSOATS	3	1MHz	54
1 000 to 3 000	FSUATS		Average /	70
3 000 to 6 000		3	1MHz	74



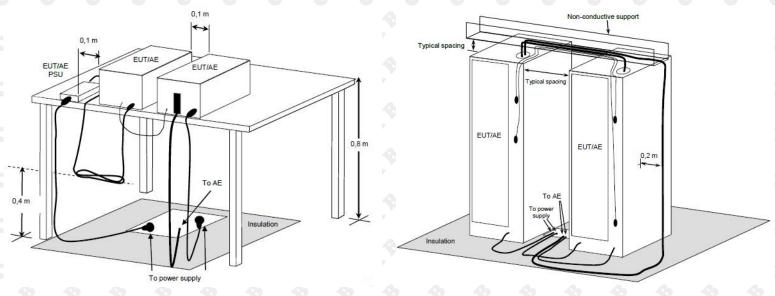
5.2.2. Block diagram of test setup

Measurement distance



For table-top equipment

For floor standing equipment



5.2.3. Test procedure

The measurement was performed in a semi-anechoic chamber.

The distance from EUT to receiving antenna is 3 meters.

Measurement was performed according to clause 7.3 of CISPR 16-2-3.

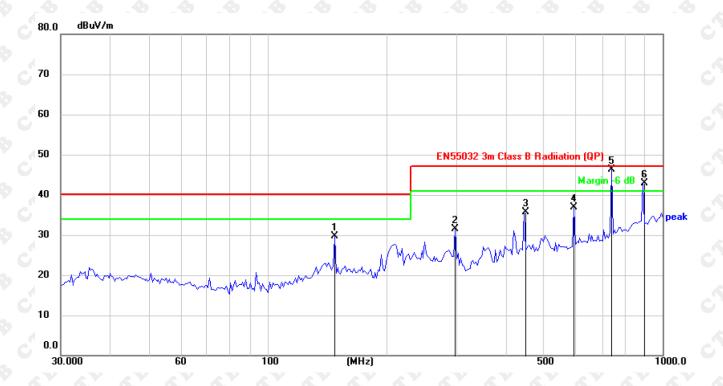
5.2.4. Test results

PASS

Please refer to the following page.



Polarization: H



No.	Mk.	Freq.	Reading Level	Correct Factor	Measure- ment	Limit	Over		Antenna Height	Table Degree	
		MHz	dBuV	dB	dBuV/m	dB/m	dB	Detector	cm	degree	Comment
1		147.9214	37.50	-7.87	29.63	40.00	-10.37	QP			
2		298.2681	38.45	-6.87	31.58	47.00	-15.42	QP			
3	4	446.4141	39.35	-3.64	35.71	47.00	-11.29	QP			
4	,	596.1772	36.48	0.46	36.94	47.00	-10.06	QP			
5	*	742.2587	43.35	2.89	46.24	47.00	-0.76	QP			
6	į (892.2909	37.40	5.46	42.86	47.00	-4.14	QP			

Note: Result=Reading+Factor
 Over Limit=Result-Limit



Polarization: V



No.	Mk.	Freq.	Reading Level	Correct Factor	Measure- ment	Limit	Over		Antenna Height	Table Degree	
		MHz	dBuV	dB	dBuV/m	dB/m	dB	Detector	cm	degree	Comment
1		34.2160	40.67	-7.46	33.21	40.00	-6.79	QP			
2		147.9214	40.24	-7.87	32.37	40.00	-7.63	QP			
3	4	446.4141	37.53	-3.64	33.89	47.00	-13.11	QP			
4	ļ	596.1772	36.65	0.46	37.11	47.00	-9.89	QP			
5	*	741.7587	42.51	2.88	45.39	47.00	-1.61	QP	100	360	
6	8	892.2909	34.44	5.46	39.90	47.00	-7.10	QP			

Note: Result=Reading+Factor Over Limit=Result-Limit



5.3. Harmonic current emissions

5.3.1. Test Setup

Harmonic & flicker	P 2 P 2 P	ST ST ST
test system	40 40 40	EUI

5.3.2. Test Procedure

Basic Standard(s)	0	EN IEC 61000-3-2:201	9
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Measurement Equipment requirement : IEC 61000-4-7

Measured Harmonics : 1 - 40

☐ Clause 7.2

☐ Clause 7.3 Table 2

☐ Clause 7.4 Table 3

This product is not defined as lighting equipment, and has rated power less than 7	75W,
therefore, no limit applies according to EN 61000-3-2	

☐ The EUT is kitchen machines as listed in the scope of IEC 60335-2-14, therefore, is deemed to conform to the harmonic current limits of this standard without further testing.

5.3.3. Test Result

N/a

No adapters ,EUT not applicable to this test.

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5.4. Voltage changes, voltage fluctuations and flicker

5.4.1. Test Setup



5.4.2. Test Procedure

Basic Standard(s) EN 61000-3-3:2013/A1:2019

IEC 61000-4-15 Measurement Equipment requirement

Limits Clause 5

5.4.2.1 Definition

Flicker: impression of unsteadiness of visual sensation induced by a lighting stimulus whose luminance or spectral distribution fluctuates with time.

Pst: Short-term flicker indicator the flicker severity evaluated over a short period (in minutes);

P_{st}=1 is the conventional threshold of irritability

P_{It}: long-term flicker indicator; the flicker severity evaluated over a long period (a few hours) using successive P_{st} values.

dc: the relative steady-state voltage change

d_{max}: the maximum relative voltage change

d(t): the value during a voltage change

5.4.2.2 Test Precedure

The following limits apply

- -- "P_{It}" shall not exceed 0.65.
- -- "Pst" shall not exceed 1.0.
- -- "dc" shall not exceed 3.3%.
- -- "d(t)" shall not exceed 3.3% for more than 500ms.
- -- "d_{ma:}

x" shall not exceed:
☐ 4% without additional conditions,
☐ 6% switched manually or automatically more than twice per day,
☐ 7% attended whilst in use or switched automatically for no more than twice per day or
attended while in use.
☐ For manual switch, dmax is measured in accordance with Annex B of standard,
average dmax is calculated from 24 times measurement.
☐ The EUT is unlikely to produce significant voltage fluctuations or flicker by technica
analysis and evaluation. So it is deemed to fulfil the requirements without testing.

5.4.3. Test Result

N/a

No adapters ,EUT not applicable to this test.



6. Immunity

Performance criteria

Performance criterion A

The equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss function is allowed below a performance level specified by the manufacturer, when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance. If the minimum performance level or the permissible performance loss is not specified by the manufacturer, then either of these may be derived from the product description and documentation, and by what the user may reasonably expect from the equipment if used as intended.

Performance criterion B

The equipment shall continue to operate as intended after the test. No degradation of performance or loss function is allowed below a performance level specified by the manufacturer, when the equipment is used as intended. During the test, degradation of performance is however allowed. No change of actual operating state or stored data is allowed. If the minimum performance level or the permissible performance loss is specified by the manufacturer, either of these may be derived from the product description and documentation and what the user may reasonably expect from equipment if used as intended.

Performance criterion C

Temporary loss of function is allowed, provided the function is self-recoverable or can be restored by operation of the controls.



6.1. Electrostatic discharges (ESD)

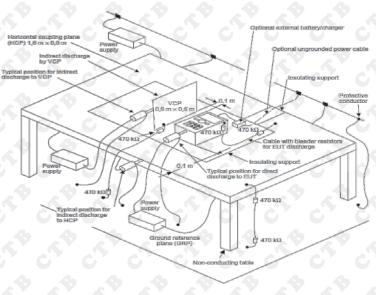
6.1.1. Test Levels and Performance Criterion

Characteristics	Test levels
Air discharge	±8 kV
Contact discharge	±4 kV

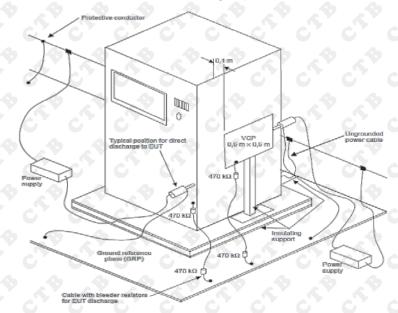
Performance criterion: B

6.1.2. Test setup

For table-top equipment



For floor standing equipment



6.1.3. Test Procedure

Measurement was performed in shielded room.

Measurement procedure was applied according to EN 61000-4-2 clause 8.

The test method and equipment were specified by EN 61000-4-2.

6.1.4. Test Result

PASS

Please refer to the following page.

No.	Location of discharge	Polarity	Discharge	Number of discharges	Test level kV	Result
1	HCP C C	P&N	С	10	4	PASS
2	VCP	P&N	С	10	4	PASS
3	Points on conductive surface	P&N	С	10	4	PASS
4	Points on non-conductive surface	P&N	Α	10	8	PASS
LCD.	- Horizontal coupling plate VCP - V	/ertical counti	na plato M	- Negative	P - Positive	h Oh

A = Air discharge C = Contact discharge



6.2. Electromagnetic field

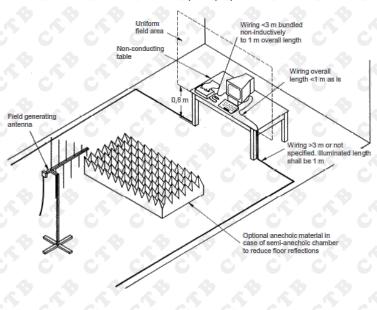
6.2.1. Test Levels and Performance Criterion

Characteristics	Test levels	Test levels		
Frequency range 80 MHz to 1 000 MH		1 800MHz, 2 600MHz,		
· · · · · · · · · · · · · · · · · · ·	0 0 0 0	3 500MHz, 5 000MHz		
Test level	3 V/m (unmodulated)	3 V/m (unmodulated)		
Modulation	1 kHz, 80 % AM, sine wave	1 kHz, 80 % AM, sine wave		

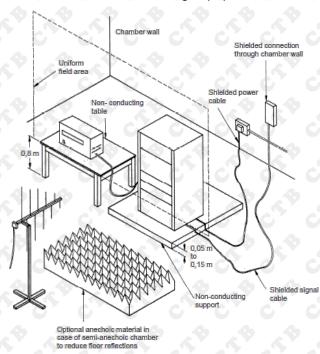
Performance criterion: A

6.2.2. Test setup

For table-top equipment



For floor standing equipment



6.2.3. Test Procedure

Measurement was performed in full-anechoic chamber.

Measurement procedure was applied according to EN 61000-4-3 clause 8.

The test method and equipment was specified by EN 61000-4-3.

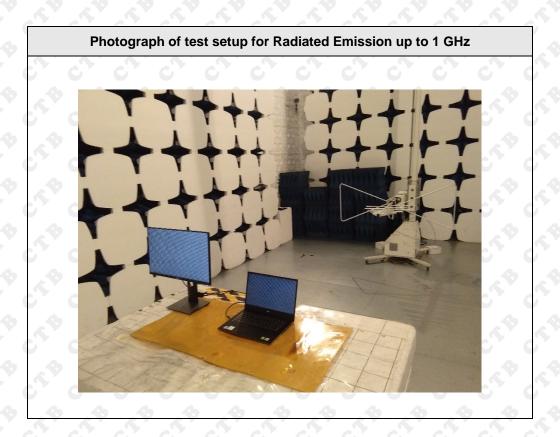
6.2.4. Test Result

PASS

Enclosure	Horizontal	Vertical
Front	PASS	PASS
Right Side	PASS	PASS
Left Side	PASS	PASS
Rear	PASS	PASS



7. Photographs of test setup





8. Photographs of EUT







End of report